

**Search Notes**

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Examiner

Yong D. Pak

Applicant(s)/Patent under  
Reexamination

HAUER ET AL.

Art Unit

1652

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
stic: seq id no:2	6/12/2007	YP
stn/east: see search history	6/12/2007	YP
inventor search	6/12/2007	YP